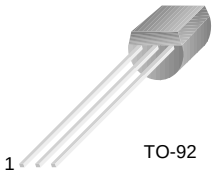
FAIRCHILD SEMICONDUCTOR®

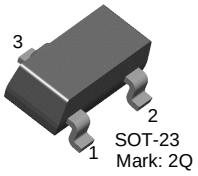
2N5086/2N5087/MMBT5087

PNP General Purpose Amplifier

- This device is designed for low level, high gain, low noise general purpose amplifier applications at collector currents to 50mA.



1. Emitter 2. Base 3. Collector



1. Base 2. Emitter 3. Collector

Absolute Maximum Ratings* T_a=25°C unless otherwise noted

Symbol	Parameter	Value	Units
V_{CEO}	Collector-Emitter Voltage	-50	V
V_{CBO}	Collector-Base Voltage	-50	V
V_{EBO}	Emitter-Base Voltage	-3.0	V
I_C	Collector current - Continuous	-100	mA
T_J, T_{stg}	Junction and Storage Temperature	-55 ~ +150	°C

* These ratings are limiting values above which the serviceability of any semiconductor device may be impaired.

NOTES:
1. These ratings are based on a maximum junction temperature of 150 degrees C.
2. These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.

Electrical Characteristics T_a=25°C unless otherwise noted

Symbol	Parameter	Test Condition		Min.	Max.	Units
Off Characteristics						
$V_{(BR)CEO}$	Collector-Emitter Breakdown Voltage *	I_C = -1.0mA, I_B = 0		-50		V
$V_{(BR)CBO}$	Collector-Base Breakdown Voltage	I_C = -100µA, I_E = 0		-50		V
I_{CEO}	Collector Cutoff Current	V_{CB} = -10V, I_E = 0 V_{CB} = -35V, I_E = 0			-10 -50	nA nA
I_{CBO}	Emitter Cutoff Current	V_{EB} = -3.0V, I_C = 0			-50	nA
On Characteristics						
h_{FE}	DC Current Gain	I_C = -100µA, V_{CE} = -5.0V	5086	150	500	
			5087	250	800	
		I_C = -1.0mA, V_{CE} = -5.0V	5086	150		
			5087	250		
		I_C = -10mA, V_{CE} = -5.0V	5086	150		
			5087	250		
$V_{CE(sat)}$	Collector-Emitter Saturation Voltage	I_C = -10mA, I_B = -1.0mA			-0.3	V
$V_{BE(on)}$	Base-Emitter On Voltage	I_C = -1.0mA, V_{CE} = -5.0V			-0.85	V
Small Signal Characteristics						
f_T	Current Gain Bandwidth Product	I_C = -500µA, V_{CE} = -5.0V, f = 20MHz		40		MHz
C_{cb}	Collector-Base Capacitance	V_{CB} = -5.0V, I_E = 0, f = 100KHz			4.0	pF
h_{fe}	Small-Signal Current Gain	I_C = -1.0mA, V_{CE} = -5.0V, f = 1.0KHz	5086 5087	150 250	600 900	
NF	Noise Figure	I_C = -100µA, V_{CE} = -5.0V R_S = 3.0kΩ, f = 1.0KHz	5086 5087		3.0 2.0	dB dB
		I_C = -20µA, V_{CE} = -5.0V R_S = 10kΩ f = 10Hz to 15.7KHz	5086 5087		3.0 2.0	dB dB

* Pulse Test: Pulse Width ≤ 300µs, Duty Cycle ≤ 2.0%

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Thermal Characteristics T_a=25°C unless otherwise noted

Symbol	Parameter	Max.		Units
		2N5086 2N5087	*MMBT5087	
P_D	Total Device Dissipation Derate above 25°C	625 5.0	350 2.8	mW mW/°C
$R_{\theta JC}$	Thermal Resistance, Junction to Case	83.3		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	200	357	°C/W

* Device mounted on FR-4 PCB 1.6" × 1.6" × 0.06."

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Typical Characteristics

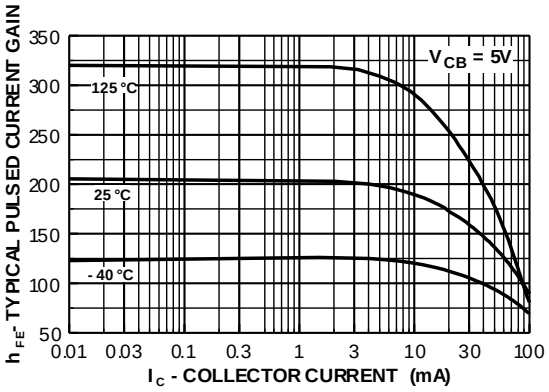

Figure 1. Typical Pulsed Current Gain vs Collector Current

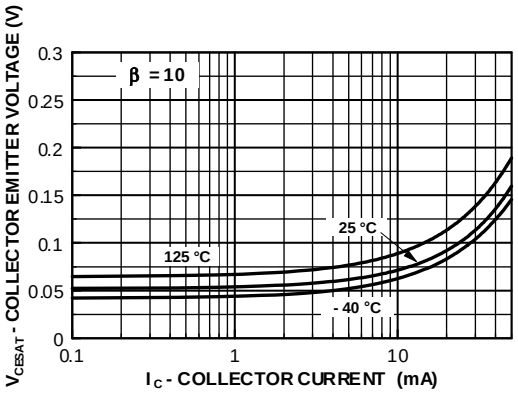

Figure 2. Collector-Emitter Saturation Voltage vs Collector Current

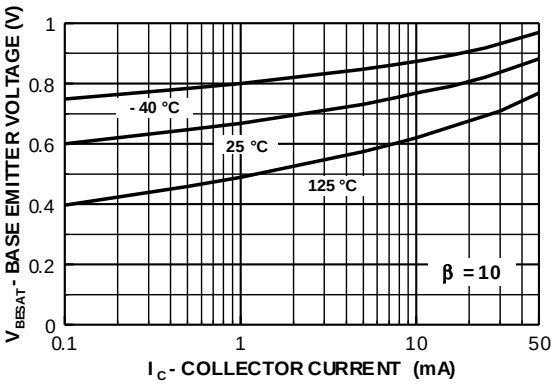

Figure 3. Base-Emitter Saturation Voltage vs Collector Current

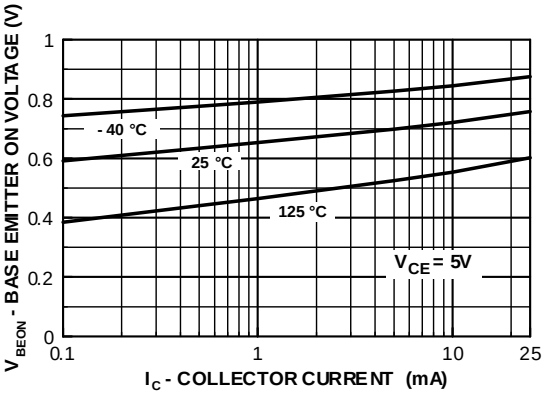

Figure 4. Base-Emitter On Voltage vs Collector Current

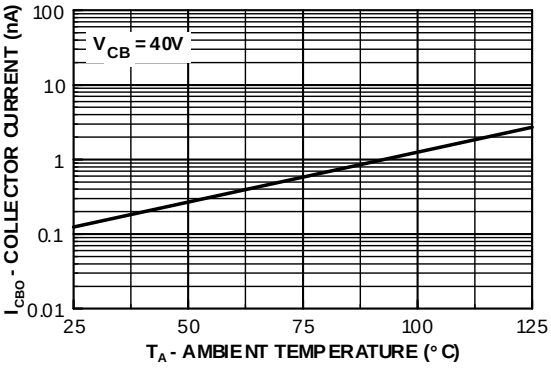

Figure 5. Collector Cutoff Current vs Ambient Temperature

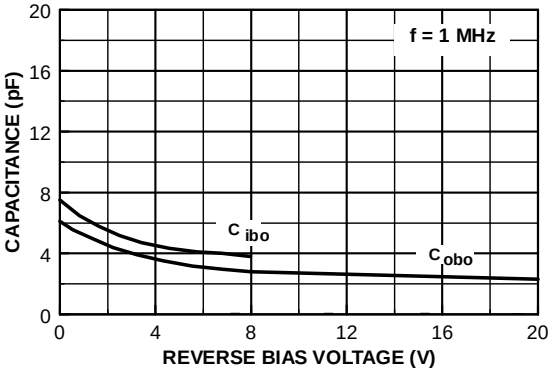

Figure 6. Input and Output Capacitance vs Reverse Voltag

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Typical Characteristics(Continuce)

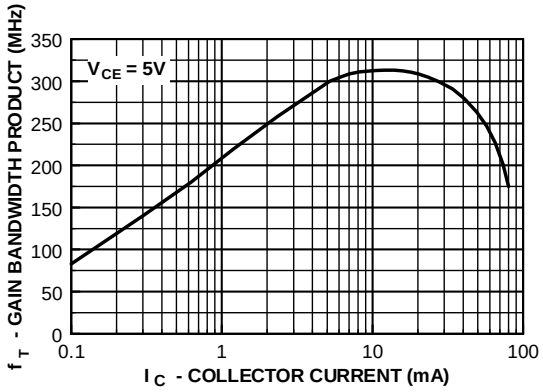

Figure 7. Gain Bandwidth Product vs Collector Current

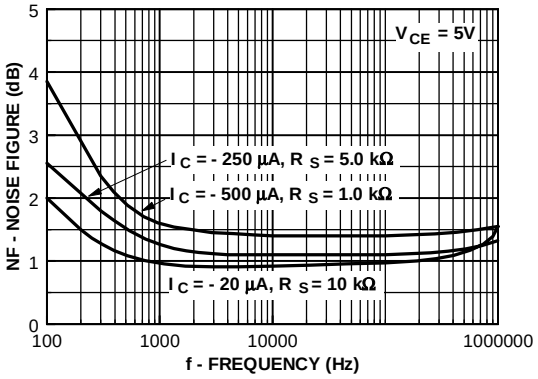

Figure 8. Noise Figure vs Frequency

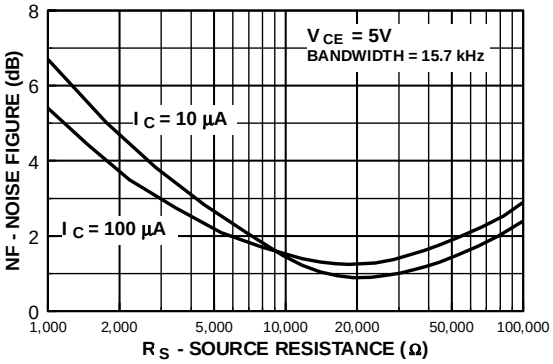

Figure 9. Wideband Noise Frequency vs Source Resistance

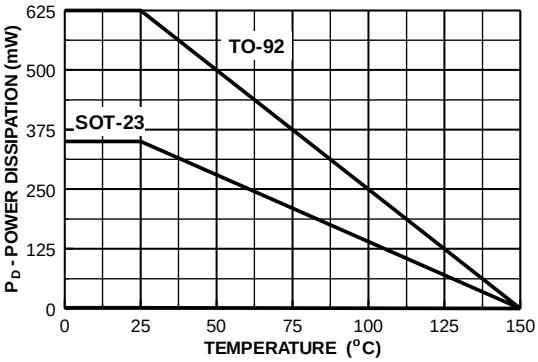

Figure 10. Power Dissipation vs Ambient Temperature

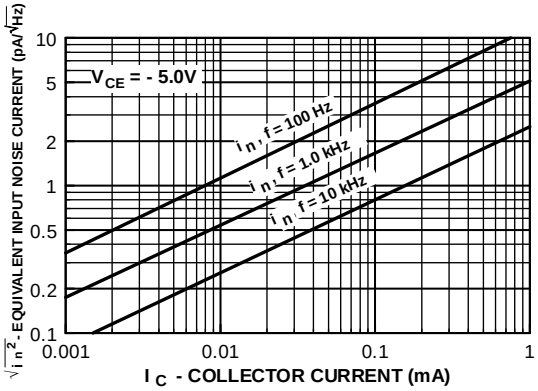

Figure 11. Equivalent Input Noise Current vs Collector Current

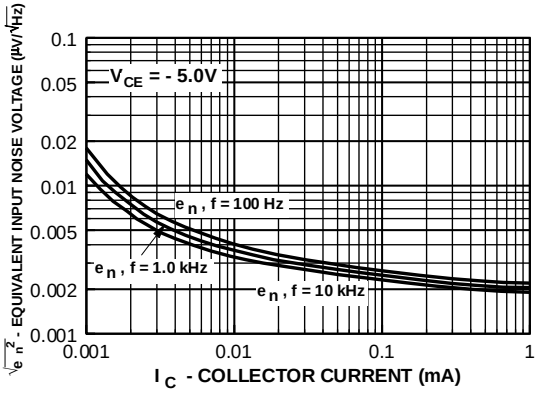

Figure 12. Equivalent Input Noise Voltage vs Collector Current

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Typical Characteristics (Continuce)

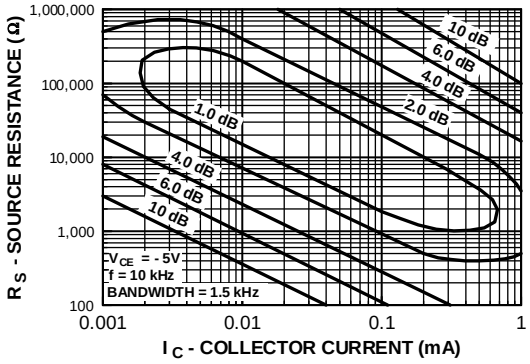

Figure 13. Contours of Constanct Narrow Band Noise Figure

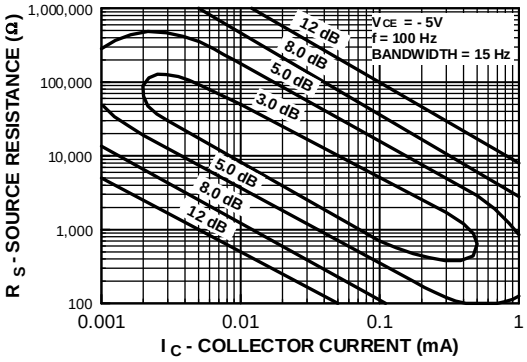

Figure 14. Contours of Constanct Narrow Band Noise Figure

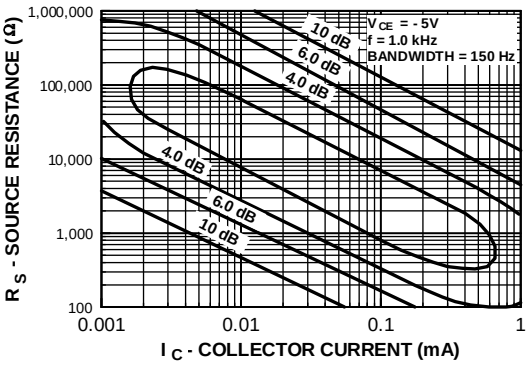

Figure 15. BContours of Constant Narrow Band Noise Figure

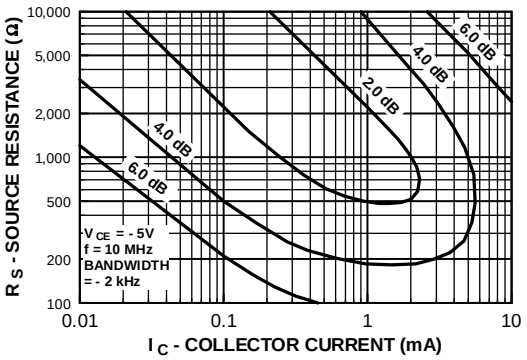

Figure 16. Contours of Constant Narrow Band Noisd Figure

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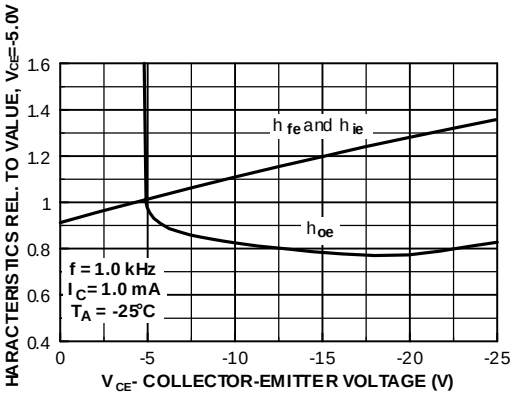
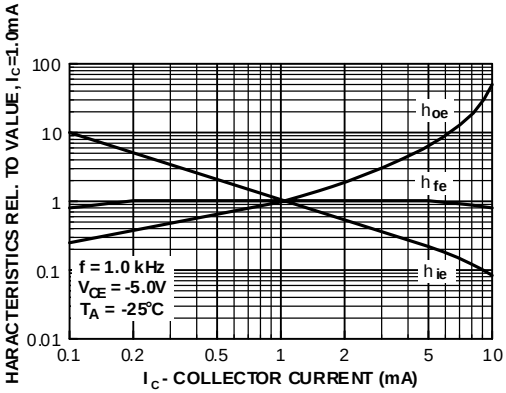
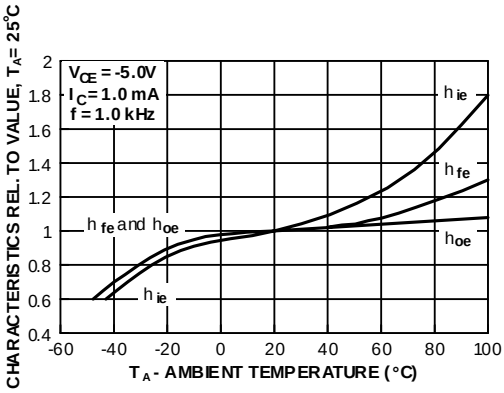
Typical Common Emitter Characteristics (f = 1.0KHz)



Typical Common Emitter Characteristics



Typical Common Emitter Characteristics



Typical Common Emitter Characteristics

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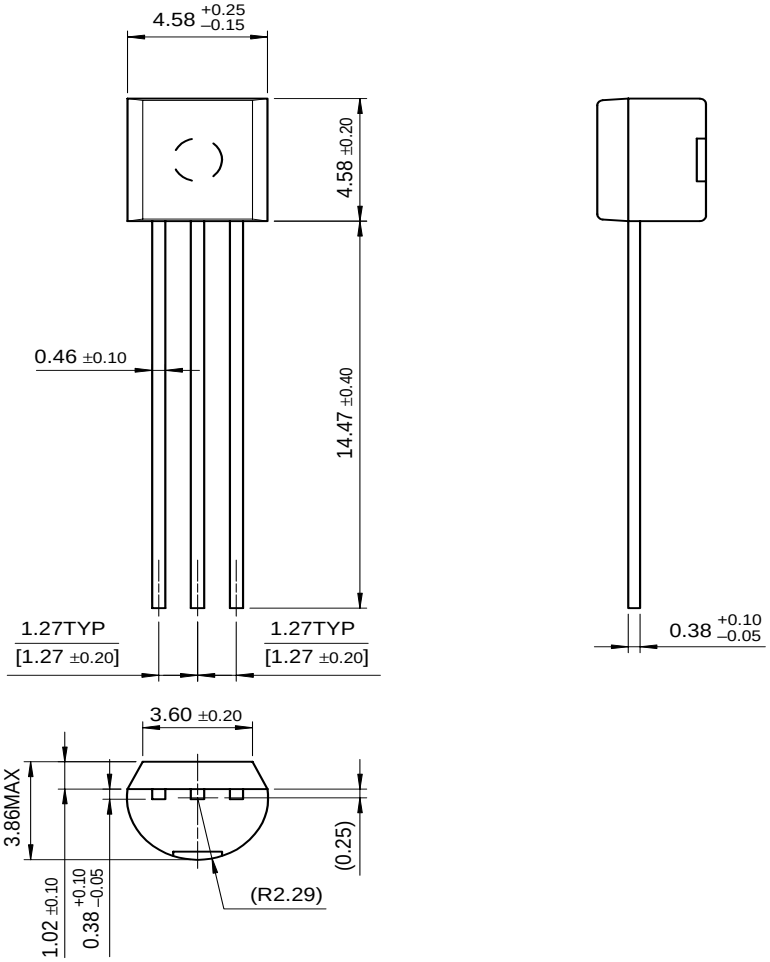
Package Dimensions

TO-92



Dimensions in Millimeters

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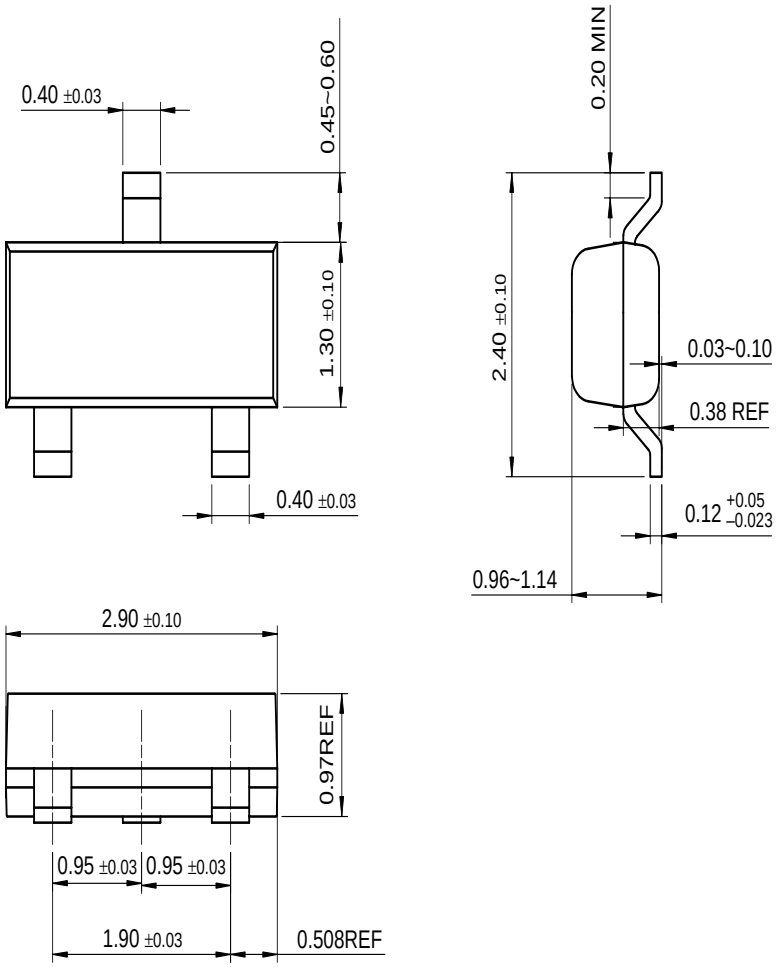
Package Dimensions (Continued)

SOT-23



Dimensions in Millimeters

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No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.

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